Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/722,441	KONDO, TAKAYUKI	
Examiner	Art Unit	
James D. Stein	2874	

SEARCHED					
Subclass	Date	Examiner			
14,15,24, 49	7/26/2005	JDS			
141	7/26/2005	JDS			
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	Subclass 14,15,24, 49 141	Subclass Date 14,15,24, 49 7/26/2005 141 7/26/2005			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
385	14,2 4 ,49	7/26/2005	JDS		
398	141	7/26/2005	JDS		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
See attached EAST search History	7/26/2005	JDS			
IEEE and INSPEC: substrate, tile, trasmitter, receiver, emitter, detector, mux, demux, multiplex, waveguide, display,	7/26/2005	JDS			
US-PGPUB interference search see attached EAST search history	7/26/2005	JDS			
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